

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

241677US2

SERIAL NO.

10/642,222

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Kenji YOSHIDA, et al.

FILING DATE

August 18, 2003

GROUP

2812

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
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<del>AO</del>	AO	10-12687	01/16/1998	JAPAN	<del>/</del>	X
<del>AP</del>	AP	3-254126	11/13/1991	JAPAN	<del>/</del>	X
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## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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☐ Additional References sheet(s) attached

Examiner

Date Considered

05/11/06

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 241677US2		SERIAL NO. 10/642,222	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Kenji YOSHIDA, et al.			
				FILING DATE August 18, 2003		GROUP 2812	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
<i>AS</i>	AA	5,930,587	07/27/1999	V. W. RYAN			
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
<del></del>	AW	K. YOSHIDA, et al., International Electron Device Meeting, pages 753-756, "STRESS-INDUCED VOIDING PHENOMENA FOR AN AACTURAL CMOS LSI INTERCONNECTS", December 2002					
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Examiner <i>Andrew C. Stevenson</i>					<input type="checkbox"/> Additional References sheet(s) attached		
Date Considered <i>05/11/06</i>							
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